

Atsushi Waseda

List of Publications by Year in descending order

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33
papers

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citing authors

#	ARTICLE	IF	CITATIONS
1	Determination of the Avogadro Constant by Counting the Atoms in a $\langle \text{mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML" display="inline" \rangle \langle \text{mml:mmultiscripts} \rangle \langle \text{mml:mi} \rangle \text{Si} \langle \text{mml:mi} \rangle \langle \text{mml:mprescripts} \rangle \langle \text{mml:none} \rangle \langle \text{mml:mn} \rangle 28 \langle \text{mml:mn} \rangle \langle \text{mml:mmultiscripts} \rangle \langle \text{mml:math} \rangle$ Crystal. Physical Review Letters, 2011, 106, 030801.	7.8	183
2	Counting the atoms in a $\langle \text{sup} \rangle 28 \langle \text{sup} \rangle \text{Si}$ crystal for a new kilogram definition. Metrologia, 2011, 48, S1-S13.	1.2	160
3	Improved measurement results for the Avogadro constant using a $\langle \text{sup} \rangle 28 \langle \text{sup} \rangle \text{Si}$ -enriched crystal. Metrologia, 2015, 52, 360-375.	1.2	143
4	A new $\langle \text{sup} \rangle 28 \langle \text{sup} \rangle \text{Si}$ single crystal: counting the atoms for the new kilogram definition. Metrologia, 2017, 54, 693-715.	1.2	92
5	Present State of the Avogadro Constant Determination From Silicon Crystals With Natural Isotopic Compositions. IEEE Transactions on Instrumentation and Measurement, 2005, 54, 854-859.	4.7	73
6	Evaluation of the molar volume of silicon crystals for a determination of the avogadro constant. IEEE Transactions on Instrumentation and Measurement, 2003, 52, 646-651.	4.7	44
7	Density comparison measurements of silicon crystals by a pressure-of-flotation method at NMIJ. Metrologia, 2004, 41, S62-S67.	1.2	36
8	Accurate density measurements of reference liquids by a magnetic suspension balance. Metrologia, 2004, 41, S84-S94.	1.2	35
9	High precision density comparison measurement of silicon crystals by the pressure of flotation method. Measurement Science and Technology, 2001, 12, 2039-2045.	2.6	30
10	Development of a silicon density standard and precision density measurements of solid materials by hydrostatic weighing. Measurement Science and Technology, 2001, 12, 2031-2038.	2.6	27
11	Homogeneity characterization of lattice spacing of silicon single crystals by a self-referenced lattice comparator. Metrologia, 2011, 48, S55-S61.	1.2	25
12	Density Evaluation of Silicon Thermal-Oxide Layers on Silicon Crystals by the Pressure-of-Flotation Method. IEEE Transactions on Instrumentation and Measurement, 2007, 56, 628-631.	4.7	18
13	Density comparison measurement of silicon by pressure of flotation method. IEEE Transactions on Instrumentation and Measurement, 2001, 50, 604-607.	4.7	16
14	Density measurements of silicon crystals by hydrostatic weighing [for Avogadro constant determination]. IEEE Transactions on Instrumentation and Measurement, 2001, 50, 616-621.	4.7	14
15	Density Measurement of a Thin-Film by the Pressure-of-Flotation Method. IEEE Transactions on Instrumentation and Measurement, 2005, 54, 882-885.	4.7	12
16	Homogeneity Characterization of Lattice Spacing of Silicon Single Crystals. IEEE Transactions on Instrumentation and Measurement, 2015, 64, 1692-1695.	4.7	11
17	Uniformity Evaluation of Lattice Spacing of $\langle \text{sup} \rangle 28 \langle \text{sup} \rangle \text{Si}$ Single Crystals. IEEE Transactions on Instrumentation and Measurement, 2017, 66, 1304-1308.	4.7	8
18	Absolute measurement of the density of silicon spheres to improve the primary density standard of NMIJ. Metrologia, 2020, 57, 025006.	1.2	6

#	ARTICLE	IF	CITATIONS
19	Comparison of Density Difference Measurements at PTB and NMIJ. IEEE Transactions on Instrumentation and Measurement, 2005, 54, 877-881.	4.7	4
20	Profile Measurement of Polished Surface with Respect to a Lattice Plane of a Silicon Crystal Using a Self-Referenced Lattice Comparator. International Journal of Automation Technology, 2011, 5, 179-184.	1.0	3
21	A Silicon d-spacing Mapping Measurement System With Resolution of 10^{-9} . , 2010, , .		2
22	Density Comparison of Isotopically Purified Silicon Single Crystals by the Pressure-of-Flotation Method. IEEE Transactions on Instrumentation and Measurement, 2011, 60, 2539-2543.	4.7	2
23	High-efficiency ultra-precision comparator for d-spacing mapping measurement of silicon. Journal of Synchrotron Radiation, 2020, 27, 577-582.	2.4	2
24	The electron - positron momentum density and Fermi surface in. Journal of Physics Condensed Matter, 1996, 8, 2413-2423.	1.8	1
25	Density measurements of silicon crystals by hydrostatic weighing. , 0, , .		1
26	Lattice spacing mapping in large silicon ingot using high resolution lattice comparator. , 0, , .		1
27	Evaluation of the molar volume of silicon crystals for a determination of the Avogadro constant. , 0, , .		1
28	Density comparison measurements of silicon crystals by pressure of flotation method. , 0, , .		0
29	Status of the international effort on the x-ray crystal density work and its progress towards a measurement of the Avogadro constant. , 2008, , .		0
30	Density measurement of a small ^{28}Si single crystal. , 2008, , .		0
31	Fast X-ray reflectivity measurement using a cooling PIN photodiode. IOP Conference Series: Materials Science and Engineering, 2011, 24, 012025.	0.6	0
32	Improvement of the self-referenced lattice comparator: From using a pencil beam to a brush beam. AIP Conference Proceedings, 2019, , .	0.4	0
33	Uniformity evaluation of lattice spacing of silicon crystals for the realization of the kilogram. Measurement: Sensors, 2021, 18, 100204.	1.7	0